Welcome Message from the General Co-Chairs and the Program Co-Chairs

Welcome to the IEEE International On-Line Testing Symposium 2007, in Heraklion, Crete, Greece!

This is the 13th year of the successful technical meeting that was initially held as a workshop from 1995 to 2002 and has been elevated to a symposium since 2003 when it was again held in a Greek island, Kos.

The On-Line Testing Workshop was created at a time when the variety of applications of electronic systems was growing rapidly and formidable increase with system complexity was experienced, leading to elevating needs for protection against field failures. Since then, more and more applications rely on integrated circuits to achieve safety, availability or security requirements, while technology scaling have moved closer to the scale of the atomic level. This has brought forth issues like aging, wearout, etc. to the field of on-line testing. This has not only impacted the high reliability industry, but also spread to all sectors of electronics applications. The design of modern electronics systems therefore needs efficient solutions combining high fault detection or tolerance with low cost and reduced time to market. The elevation of the workshop to a symposium during the last five years reflects these trends and the recognition of this event as a major forum for sharing ideas and experiences among those working in this field.

The technical program this year is extended by one day to include a special full-day tutorial on soft errors (Sunday, July 8 2007). The tutorial is part of the IEEE Computer Society Test Technology Technical Council (TTTC) Test Technology Educational Program (TTEP) 2007.

The regular technical program runs from Monday, July 9 2007 to Wednesday, July 11 2007. It includes three exciting keynote and invited talks given by key industry speakers. The technical program also includes 11 regular paper sessions with 33 papers and an interactive poster session with 12 papers. The regular technical presentations cover a wide variety of the most important topics of the technical area. Three special sessions and a panel are also organized where experts in the specific topics elaborate and present their point of view for the present and future emerging problems.

This year, we have a very strong paper submissions flow coming from around the world and a total of twenty two different countries and it has made the job of selecting the top papers difficult. We regret to have to leave many good papers behind.

We wish you an enjoyable IEEE International On-Line Testing Symposium 2007, and hope that you enjoy all it offers: the tutorial, technical program, interactions with your colleagues, and beautiful sunny scenery of Crete!

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